Testing Laboratory
3023

Test Report No:
2660649R-RFJPV02S-C

TEST REPORT
Japan Rules & Regulations

Product Name	Module
Brand Name	ASUS
Model No.	MPRFMODULE3
Applicant´s Name / Address	ASUSTeK COMPUTER INC. 1F., No. 15, Lide Rd., Beitou Dist., Taipei City 112, Taiwan
Manufacturer's Name	ASUSTeK COMPUTER INC.
Test Method Requested, Standard	MIC Notice No.88 Appendix No.43 Item 19 of Article 2 Paragraph 1
Verdict Summary	IN COMPLIANCE
Documented by Jinn Chen	Jinn Chen
Approved by Steven Tsai	Steven Tsai
Date of Receipt	2026/06/24
Date of Issue	2026/09/04
Report Version	V1.0

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Competences and Guarantees

DEKRA is a testing laboratory competent to carry out the tests described in this report.
In order to assure the traceability to other national and international laboratories, DEKRA has a calibration and maintenance program for its measurement equipment.

DEKRA guarantees the reliability of the data presented in this report, which is the result of the measurements and the tests performed to the item under test on the date and under the conditions stated in the report and it is based on the knowledge and technical facilities available at DEKRA at the time of performance of the test.

DEKRA is liable to the client for the maintenance of the confidentiality of all information related to the item under test and the results of the test.

The results presented in this Test Report apply only to the particular item under test established in this document.

IMPORTANT: No parts of this report may be reproduced or quoted out of context, in any form or by any means, except in full, without the previous written permission of DEKRA.

General Conditions

1. The test results relate only to the samples tested.
2. The test results shown in the test report are traceable to the national/international standard through the calibration report of the equipment and evaluated measurement uncertainty herein.
3. This report must not be used to claim product endorsement by TAF or any agency of the government.
4. The test report shall not be reproduced without the written approval of DEKRA Testing and Certification Co., Ltd.
5. Measurement uncertainties evaluated for each testing system and associated connections are given here to provide the system information for reference. Compliance determinations do not take into account measurement uncertainties for each testing system, but are based on the results of the compliance measurement.

Revision History

Version	Description	Issued Date
V1.0	Initial issue of report	2026/09/04

Summary of Test Result

Report Clause	Test Items	Result (PASS/FAIL)	Remark
3	Antenna Power, Antenna Power Tolerance and E.I.R.P	PASS	-
4	Occupied Bandwidth	PASS	-
5	Frequency Tolerance	PASS	-
6	Dwell Time	PASS	-
7	Unwanted Emission Strength	PASS	-
8	Secondary Radiated Emission Strength	PASS	-
9	Interference Prevention Function	PASS	-

Comments and Explanations
The declared of product specification for EUT presented in the report are provided by the manufacturer, and the manufacturer takes all the responsibilities for the accuracy of product specification.

1. General Information

1.1. EUT Description

Frequency Band	2400 ~ 2483.5 MHz		
Operating Frequency	2404 ~ 2478 MHz		
Channel Number	37 Channels		
Type of Modulation	GFSK (2 Mbps)		
Declared Antenna Power	Normal Operation	GFSK (2 Mbps)	0.09 mW/MHz
	AFH Operation	GFSK (2 Mbps)	0.67 mW/MHz

Antenna Information				
No.	Brand Name	Part No.	Type	Gain (dBi)
1	ASUS	20LT0-000UZ000	PIFA	3.24

Working Frequency of Each Channel							
Channel	Frequency	Channel	Frequency	Channel	Frequency	Channel	Frequency
01	2404	02	2406	03	2408	04	2410
05	2412	06	2414	07	2416	08	2418
09	2420	10	2422	11	2424	13	2428
14	2430	15	2432	16	2434	17	2436
18	2438	19	2440	20	2442	21	2444
22	2446	23	2448	24	2450	25	2452
26	2454	27	2456	28	2458	29	2460
30	2462	31	2464	32	2466	33	2468
34	2470	35	2472	36	2474	37	2476
38	2478	-	-	-	-	-	-

Note: Only channels listed in the table are supported.

1.2. EUT Information

EUT Power Type	From DC 3.3V			
EUT Function	☒	Point-to-multipoint	☐	Point-to-point

1.3. Testing Location Information

Testing Location Information			
Test Laboratory：DEKRA Testing and Certification Co., Ltd.			
V	Address	No. 85, Wenlin St., Linkou Dist., New Taipei City 244017, Taiwan, R.O.C.	
	Performed Location	No. 26, Huaya 1st Rd., Guishan Dist.,Taoyuan City 333411, Taiwan, R.O.C.	
	Phone/Fax Number	TEL: +886-3-275-7255	FAX: +886-3-327-8031
	Site Description	Accredited by TAF	
		Accredited Number: 3023	
	Address/ Performed Location	No.372-2, Sec. 4, Zhongxing Rd., Zhudong Township, Hsinchu County 31061, Taiwan, R.O.C.	
	Phone/Fax Number	TEL: +886-3-582-8001	FAX: +886-3-582-8958
	Site Description	Accredited by TAF	
		Accredited Number: 3024	
	Address/ Performed Locatio	No.372, Sec. 4, Zhongxing Rd., Zhudong Township, Hsinchu County 31061, Taiwan, R.O.C.	
	Phone/Fax Number	TEL: +886-3-582-8001	FAX: +886-3-582-8958
	Site Description	Accredited by TAF	
		Accredited Number: 3024	

1.4. Ambient Conditions In The Laboratory

Performed Item	Items	Required	Actual	Test Date	Tested By
RF Conducted Emission	Temperature (°C)	5~35 °C	24.3~25.2 °C	2026/07/15 ~ 2026/07/16	Kevin Lai
	Humidity (%RH)	45~85 %	61.5~68.6 %		

1.5. Measurement Uncertainty

Uncertainties have been calculated according to the DEKRA internal document. The reported expanded uncertainties are based on a standard uncertainty multiplied by a coverage factor of k=2, providing a level of confidence of approximately 95%.

Measurement uncertainties evaluated for each testing system and associated connections are given here to provide the system information for reference. Compliance determinations do not take into account measurement uncertainties for each testing system, but are based on the results of the compliance measurement.

Test item	Uncertainty
Antenna Power, Antenna Power Tolerance and E.I.R.P	Spectrum Analyzer: ±2.13 dB Power Meter: ±1.06 dB
Occupied Bandwidth	±1580.61 Hz
Frequency Tolerance	±1580.61 Hz
Dwell Time	±0.65 %
Unwanted Emission Strength	±2.13 dB
Secondary Radiated Emission Strength	±2.13 dB
Interference Prevention Function	N/A

1.6. List of Test Equipment

For Conducted Measurements / HY-SR02

	Equipment	Manufacturer	Model No.	Serial No.	Cal. by	Cal. Method	Cal. Date	Due Date
V	DC Power Supply	KEYSIGHT	E36234A	MY59001234	ETC	*(c)	2025/10/27	2026/10/26
V	Spectrum Analyzer	R&S	FSV30	103464	ETC	*(c)	2026/07/08	2027/07/07
V	Power Meter	Anritsu	ML2496A	1947001	ETC	*(c)	2025/12/22	2026/12/21
V	Power Sensor	Anritsu	MA2411B	1911082	ETC	*(c)	2025/12/22	2026/12/21
V	Power Sensor	Anritsu	MA2411B	1911083	ETC	*(c)	2025/12/22	2026/12/21

Note:

1. All equipment is calibrated every year.
2. The test instruments marked with “V” are used to measure the final test results.
3. Test Software Version: DTC_RF_Tool_Release V2.1.2.
4. a) Calibration conducted by the National Institute of Information and Communications Technology (NICT) (hereinafter referred to as "NICT") or a designated calibration agency under Article 102-18 paragraph (1).
   b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992).
   c) Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated agency under Article 102-18 paragraph (1).
   d) Calibration conducted by using other equipment that listed above from a) to c).

2. Test Configuration of EUT

2.1. Test Condition

EUT Operational Condition	
Testing Voltage	DC 3.3V (Power by test fixture)

2.2. Power Supply Voltage Fluctuation

Voltage Test Item	Test Voltage	Voltage Meter Reading Value
Nominal Voltage	DC 3.3V	DC 1.8V
Highest Voltage	DC 3.63V	DC 1.8V
Lowest Voltage	DC 2.97V	DC 1.8V

Note:

1. The Voltage supply for J7 pin 4 is DC 1.8V.
2. The internal supply gives a fluctuation value less than 1 % (Around 0% from max. to min.)

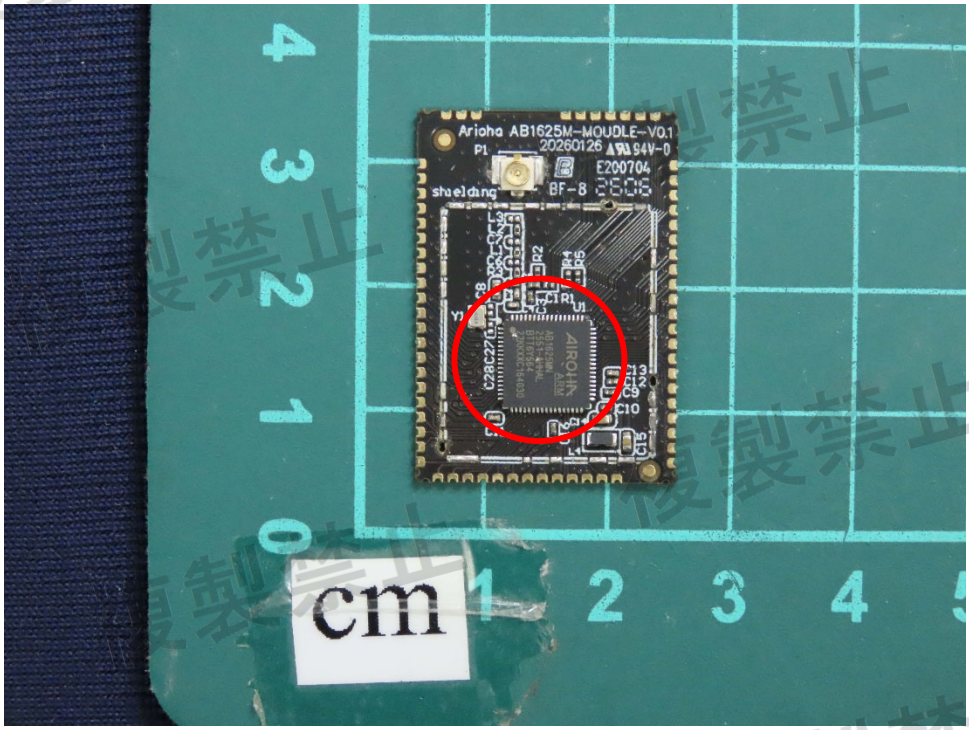
2.3. Test Frequency Mode

Test Software Version	AB1620_Airoha_Tool_Kit(ATK) / Version 1.1.0.51

Modulation or Mode	Frequency (MHz)	Power Setting
GFSK (2 Mbps)	2404	52
	2408	52
	2412	52
	2440	52
	2478	52

2.4. RF and IF Section Must be Tamper Requirement

Requirement	Comments	Result
RF, IF and Modulation section must be tamper	☐Use Special Screw ☒Metal Shielding is Soldered ☒Use Quad Flat No-Lead (QFN) (Please refer to the attachment: EUT Detailed Photographs)	Complete
	☒RF module/Chip pin >10 ☒RF module/Chip pins distance <1.5mm (Please refer to the attachment: EUT Detailed Photographs)	Complete



2.5. Measurement Configuration

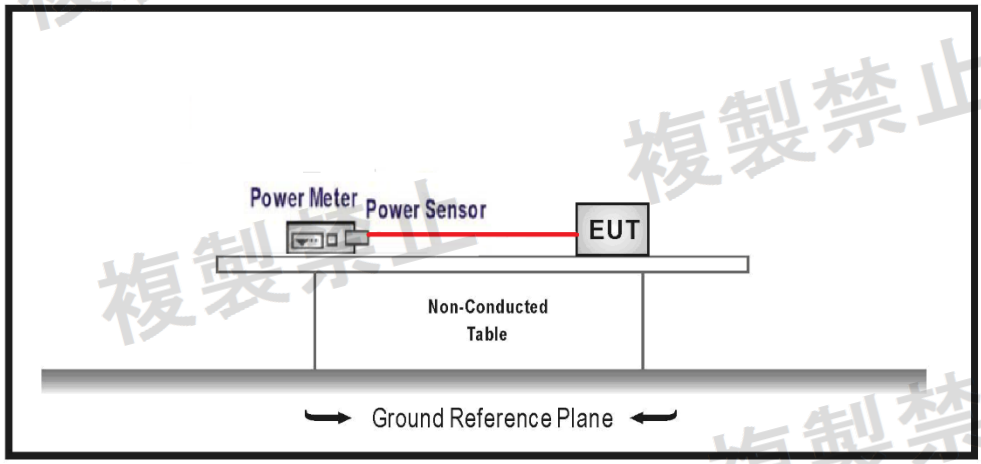
Tests Item	Antenna Power, Antenna Power Tolerance and E.I.R.P Occupied Bandwidth Frequency Tolerance Dwell Time Unwanted Emission Strength Secondary Radiated Emission Strength Interference Prevention Function
Test Condition	Conducted measurement at transmit chains

Note:

1. Determining compliance shall be based on the results of the compliance measurement, not taking into account measurement instrumentation uncertainty.
2. Pre-Scan has been conducted to determine the worst-case mode from all possible combinations between available modulations, data rates and antenna ports (if EUT with antenna diversity architecture).
3. After checking the fluctuation of input voltage to the circuit of the radio part (excluding the power supply) of the equipment to be tested, the fluctuation less than +/- 1 % when input voltage from an external supply into the equipment fluctuates +/- 10%, therefore, the test is carried out only at the normal voltage.

3. Antenna Power, Antenna Power Tolerance and E.I.R.P.

3.1. Test Setup



3.2. Test Limit

Antenna Power: ≦3mW/MHz

Antenna Power Tolerance: ≦+20%

EIRP: ≦6.91dBm/MHz

3.3. Test Method

According to MIC Notice No. 88 Annex 43.

3.4. Test Procedure

a. Connect a high-frequency power meter to the output of the dummy load (attenuator) and measure the output power.

b. Output power shall be as follows.

   (a) Value of a continuous wave.

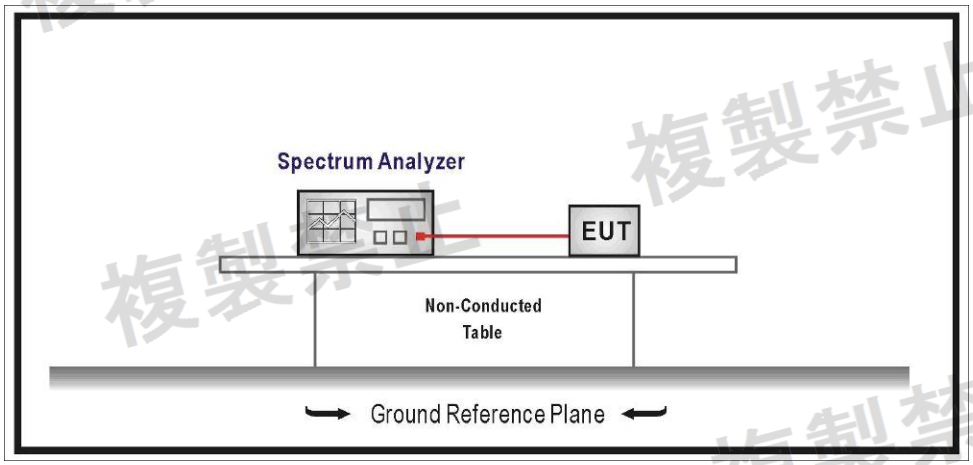
   (b) Calculate the output power per 1 MHz by spread bandwidth and duty cycle.

3.5. Test Result of Antenna Power, Antenna Power Tolerance and E.I.R.P.

Refer as Appendix A

4. Occupied Bandwidth

4.1. Test Setup



4.2. Test Limit

≦ 83.5 MHz

4.3. Test Method

According to MIC Notice No. 88 Annex 43.

4.4. Test Procedure

A spectrum analyzer or similar device shall be used to observe a sample of the modulated transmitter's radio frequency power output.

(a) A positive peak detector function must be used.

(b) A measurement instrument with an integrated 99% power bandwidth function may be used to automate the test process.

(c) The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slowly, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.

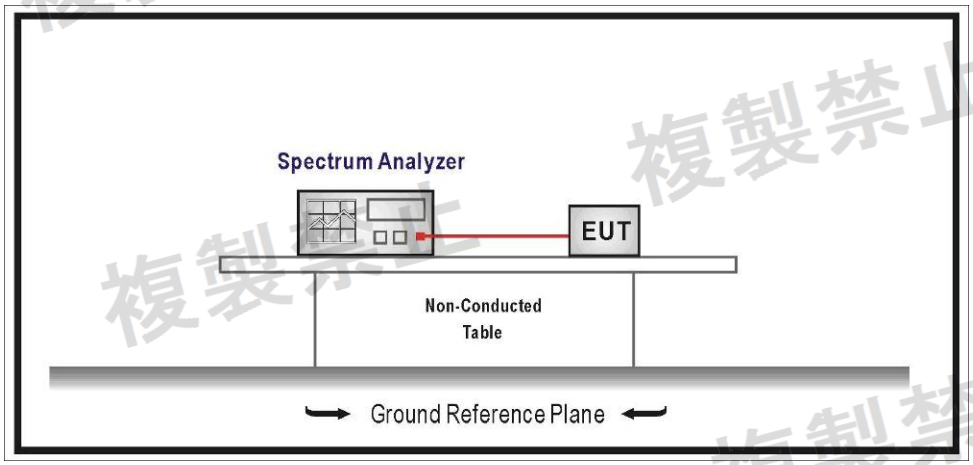
(d) 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

4.5. Test Result of Occupied Bandwidth

Refer as Appendix B

5. Frequency Tolerance

5.1. Test Setup



5.2. Test Limit

± 50 ppm

5.3. Test Method

According to MIC Notice No. 88 Annex 43.

5.4. Test Procedure

A spectrum analyzer or similar device shall be used to observe a sample of the unmodulated or modulated transmitter's radio frequency power output.

(a) A positive peak detector function must be used.

(b) The measurement instrument bandwidth and span must be set sufficiently wide, and the scan time set sufficiently slowly, to ensure all products of the unmodulated signal are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.

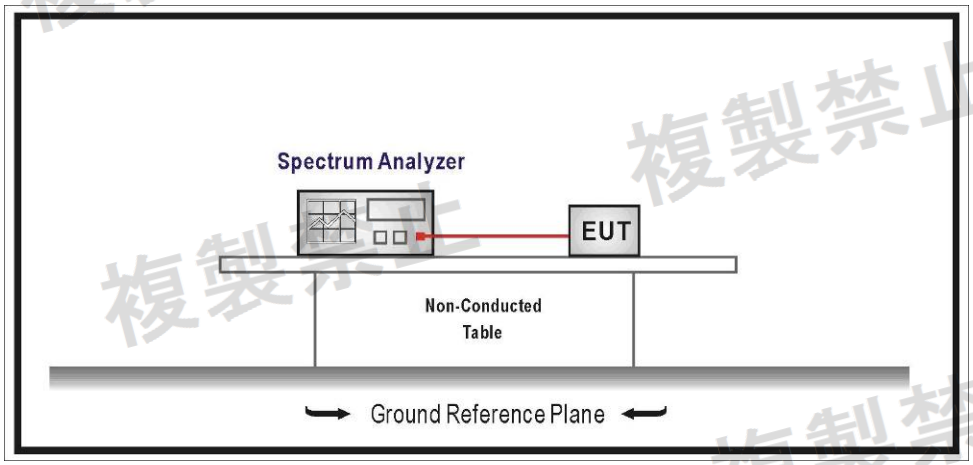
(c) 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

5.5. Test Result of Frequency Tolerance

Refer as Appendix C

6. Dwell Time

6.1. Test Setup



6.2. Test Limit

≦ 0.4 sec

6.3. Test Method

According to MIC Notice No. 88 Annex 43.

6.4. Test Procedure

A spectrum analyzer or similar device shall be used to observe a sample of the modulated transmitter's radio frequency power output.

(a) A positive peak detector function must be used.

(b) The center frequency is set to the test frequency and the span is switched to zero.

(c) The measurement instrument bandwidth must be set sufficiently with, and, the scan time set sufficiently slowly, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.

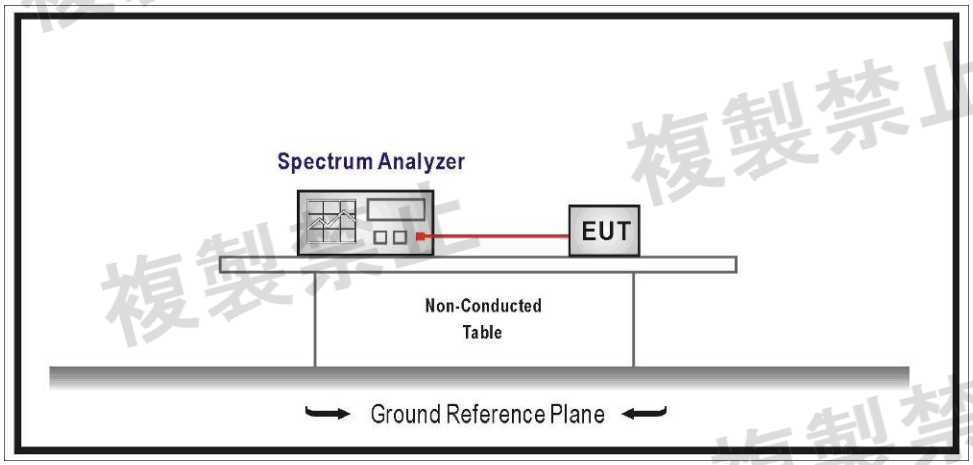
(d) "Single sweep" mode may be used to capture a packet over a single scan.

6.5. Test Result of Dwell Time

Refer as Appendix D

7. Unwanted Emission Strength

7.1. Test Setup



7.2. Test Limit

≤ 2.5uW/MHz for 30 MHz < f < 2387 MHz

≤ 25uW/MHz for 2387 MHz ≤ f < 2400 MHz

≤ 25uW/MHz for 2483.5 MHz < f ≤ 2496.5 MHz

≤ 2.5uW/MHz for 2496.5 MHz < f < 12500 MHz

7.3. Test Method

According to MIC Notice No. 88 Annex 43.

7.4. Test Procedure

The EUT is connected to the spectrum analyzer and it is configured at maximum output power in the different test channels.

(a) A positive peak detector function must be used.

(b) The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slow, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.

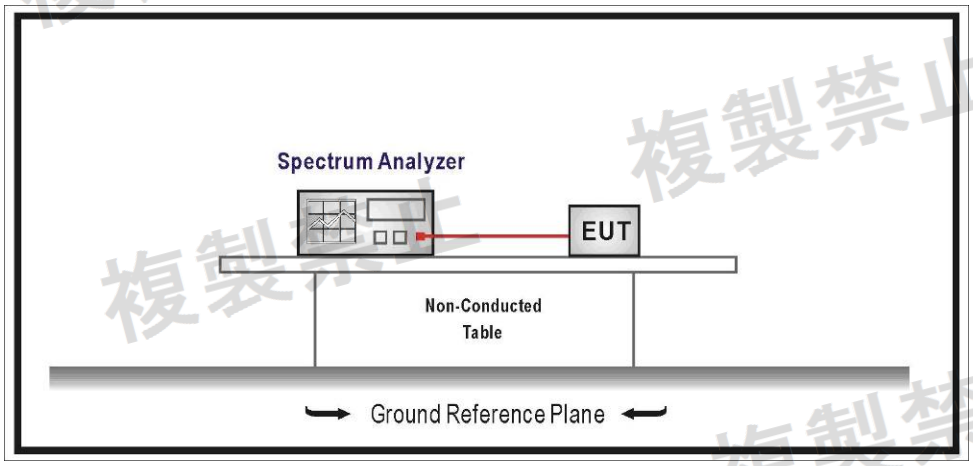
(c) 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

7.5. Test Result of Unwanted Emission Strength

Refer as Appendix E

8. Secondary Radiated Emission Strength

8.1. Test Setup



8.2. Test Limit

≤ 4nW for 30 MHz < f < 1000 MHz

≤ 20nW for 1000 MHz ≤ f < 12500 MHz

8.3. Test Method

According to MIC Notice No. 88 Annex 43.

8.4. Test Procedure

The EUT is connected to the spectrum analyzer and it is configured in reception mode in the different test channels.

(a) A positive peak detector function must be used.

(b) The measurement instrument bandwidth and span must be set sufficiently with, and, the scan time set sufficiently slowly, to ensure all major modulation products are captured. Note that the measurement bandwidth should also be set sufficiently narrow to avoid adding significant error to the test result.

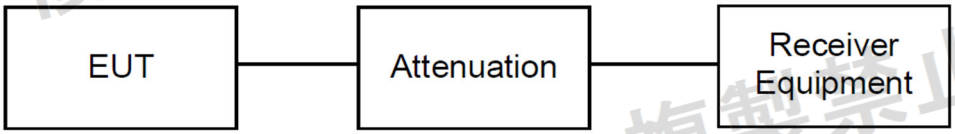
(c) 'Maximum Hold' mode may be used to accumulate the measurement result over several scans provided the emission is repetitive in nature.

8.5. Test Result of Secondary Radiated Emission Strength

Refer as Appendix F

9. Interference Prevention Function

9.1. Test Setup



9.2. Test Method

According to MIC Notice No. 88 Annex 43.

9.3. Test Procedure

Radio equipment used mainly on the same premises and automatically transmits or receives identification code.

9.4. Test Result of Interference Prevention Function

Refer as Appendix G